

## Semiconductor Wafer Test Alloys



## High Performance Precious Metal Alloys for Semiconductor Wafer Test Systems

**Application-Specific Precious Metal Alloys Developed for...** 

- Buckling Beam Probes
- Cantilever Probes
- Straight Needles
- Cobra Probes
- Pogo Pin Tips
- Vertical Probes
- Foil Probes for Laser Fabrication



 Faliney® 25
 Standard Foil

 Sizes Available:
 Sizes Available:

 Ocm x 10cm and 5cm x 5cm
 Thicknesses Range from:

 Sizes Available:
 Sizes Available:

 Ocm x 10cm and 5cm x 5cm
 Thicknesses Range from:

 Sizes Available:
 Sizes Available:

 Ocm x 10cm and 5cm x 5cm
 Thicknesses Range from:

 Sizes Available:
 Sizes Available:

 Ocm x 10cm and 5cm x 5cm
 Thicknesses Range from:

 Sizes Available:
 Sizes Available:

 Ocm x 10cm and 5cm x 5cm
 Thicknesses Range from:

 Sizes Available:
 Sizes Available:

 Sizes Available:
 Sizes Available:

 Ocm x 10cm and 5cm x 5cm
 Thicknesses Range from:

 Sizes Available:
 Sizes Available:

 Sizes Available:

Deringer-Ney's semiconductor alloys and manufacturing techniques are continually evolving to meet the increased demands for smaller component sizes. Pictured above is a cobra probe and two tip configurations commonly used in semiconductor wafer test probe cards.



ROD Straight Lengths 1.5 mm to 7mm dia (0.060 in to 0.275 in) WIRE Spooled 20 um to 1.45 mm dia

(0.0008 in to 0.57 in)

## STRIP & Ribbon Spooled

50 um to 380 um thick (0.002 in to 0.015 in) 2 mm to 89mm wide (0.080 in to 3.50 in)

## Note: Please consult factory for specific material availability and temper, or custom requirements.

| Alloy Property                         | Paliney <sup>®</sup> 7  | Paliney <sup>®</sup> H3C   | Paliney <sup>®</sup> C   | Paliney <sup>®</sup> 25  | Paliney <sup>®</sup> 23   |
|--|---|--|--|--|---|
| Solidus<br>°C                          | 1,080   | 956  | 925  | 1,090  | 1,085   |
| Density<br>g/cm³                       | 11.8  | 10.4   | 10.4   | 10.5   | 10.6  |
| Electrical Resistivity<br>μΩ-cm @ 20°C | 31.6  | 12.3   | 10.1   | 6.35   | 7.18  |
| CTE<br>1/K                             | 13.5 x 10-6   | 13.9 x 10⁻⁵  | 14.4 x 10⁻⁵  | 12.7 x 10⁵   | 12.7 x 10 <sup>-6</sup>   |
| Knoop Hardness<br>heat treated HK      | 350   | 450  | 350  | 400  | 460   |
| Yield Strength<br>MPa                  | 1,103   | 1,620  | 1,135  | 1,035  | 1,190   |
| Total Elongation %                     | 5   | 2.5  | 2  | 10   | 4   |
| Elastic Modulus<br>GPa                 | 123   | 122  | 117  | 135  | 135   |
| Alloy Configuration                    | Age Hardenable Pd-Ag-Cu Alloy   |  |  |  |   |
| Conductivity                           | 5.5% IACS   | 14% IACS   | 17% IACS   | 28% IACS   | 24% IACS  |
| Advantages                             | tarnish resistant<br>good nobility  | very high hardness<br>and conductivity<br>tarnish resistant,<br>but less noble<br>than Paliney 7 | similar tarnish<br>resistance and<br>conductivity as<br>H3C<br>better cold forming<br>ability than H3C | better tarnish<br>resistance than<br>H3C<br>excellent<br>formability<br>best conductivity<br>of all the Pd based<br>alloys | excellent tarnish<br>resistance<br>low adhesion to<br>debris<br>high hardness |
| Typical<br>Applications                | test probes -<br>cantilever, cobra,<br>vertical probe pins<br>electrodes for<br>corrosive<br>environments<br>potentiometers | test probes -<br>cantilever, cobra;<br>widely used for<br>pogo pin tips                          | test probes -<br>cantilever, cobra,<br>vertical probe pins   | test probes -<br>cantilever, cobra,<br>vertical probe pins,<br>foil probes   |   |

CONTACT US at (860) 286-6101 or www.deringerney.com

Regional Sales Manager (Asia) Mr. Philip Hsia at phsia@deringerney.com

